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## SUPPLEMENTAL MATERIALS

## for

# Pt Current Collectors Artificially Boosting Praseodymium Doped Ceria

## **Oxygen Surface Exchange Coefficients**

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**Figure S1.** Lattice oxygen concentrations (left) and thermodynamic factors (right) for various oxygen exchange materials in air. Dark gray symbols represent data obtained by studies measuring both lattice constant and oxygen nonstoichiometry data or  $k_{chem}$  and  $k_o$  data. Light gray symbols represent data obtained by studies with one measured value and at least one assumed value. The red dashed lines represent the  $C_0=8.8 \times 10^{-2} \text{ mol/cm}^3$  value commonly used in the literature <sup>1, 2</sup> (left) or the best fit to the  $\gamma_0$  data (right).  $A = Mosleh \text{ et al.}, ^3 C = Sogaard \text{ et al.}, ^4 E = ten Elshof et al., ^5 I = Tripkovic et al., ^6 J = Plonczak et al., ^2 M = Dalslet et al., ^7 O = Lane et al., ^8 P = Li et al., ^9 U = Simrick et al., ^{10} X = Egger et al., ^{11} Y = Sogaard et al., ^{12} AE = Yeh et al., ^{13} AK = Bucher et al., ^{14} AM = Girdauskaite et al., ^{15} AO = Wang et al., ^{16} AU = Ma and Nicholas, ^{17} AV = Chen et al. ^{18}$ 



**Figure S2**. Representative curvature redox cycling behavior for the uncovered PCO|YSZ samples at various temperatures (left) and fits to the reduction (middle) and oxidation (right) portions of that data. Dashed curves denote curvature relaxation data replotted as a normalized curvature (i.e. the quantity found in the left portion Eqn. 3) for  $k_{chem}$  fitting via Eqn. 3. Grayed out curves denote curvature relaxation data replotted to show that only a single process, with a single time constant, was active during each relaxation.



**Figure S3**. Representative curvature redox cycling behavior of partially-covered PCO|YSZ samples at various temperatures (left) and fits to the reduction (middle) and oxidation (right) portions of that data. Dashed curves denote curvature relaxation data replotted as a normalized curvature (i.e. the quantity found in the left portion Eqn. 3) for  $k_{chem}$  fitting via Eqn. 3. Grayed out curves denote curvature relaxation data replotted to show that only a single process, with a single time constant, was active during each relaxation.



**Figure S4**. Representative curvature redox cycling behavior for the completely-covered PCO|YSZ samples at various temperatures (left) and fits to the reduction (middle) and oxidation (right) portions of that data. Dashed curves denote curvature relaxation data replotted as a normalized curvature (i.e. the quantity found in the left portion Eqn. 3) for  $k_{chem}$  fitting via Eqn. 3. Grayed out curves denote curvature relaxation data replotted to show that only a single process, with a single time constant, was active during each relaxation.



*Figure S5.* The curvature of the completely Pt-covered PCO|YSZ samples with oxygen partial pressure cycling from air, to 10x diluted air, and back to air. Similar data for uncoated PCO|YSZ samples can be found in Ma and Nicholas.<sup>17</sup>

<u>Additional Equations Used to Convert Between Oxygen Surface Exchange Properties</u> The following equations were used, in conjunction with Eqn. 1-4, to convert between the oxygen surface

exchange properties shown in Figure 1:

$$\gamma_o = \frac{(3-\delta) * \gamma_v}{\delta}$$

[S1]

$$\gamma_o = \frac{D_{chem}}{D_o}$$

$$C_o = \frac{\sigma_{o2- * k_b * T}}{4 * F^2 * D_o}$$
[S2]

[S3]

$$C_o = \frac{3-\delta}{V_m}$$

[S4]

$$D_o = \frac{D^*}{f}$$
[S5]

where  $C_o$  is the oxygen ion concentration,  $D_o$  is the oxygen ion diffusion coefficient,  $D_{chem}$  is the oxygen chemical diffusion coefficient,  $D^*$  is the oxide ion tracer diffusion coefficient,  $\delta$  is the oxygen nonstoichiometry, F is the Faraday constant, f is the structural correlation factor (0.69 for the perovskitestructured materials needing conversion here),  $\gamma_o$  is the oxygen ion thermodynamic factor,  $\gamma_v$  is the oxygen vacancy thermodynamic factor,  $k_b$  is Boltzmann's constant,  $\sigma_o^{2-}$  is the oxygen ion conductivity, T is temperature, and  $V_m$  is the molar volume. As shown in the accompanying Excel spreadsheet, whenever possible, oxygen concentration or other data needed to perform a conversion from one surface exchange property to another was taken from data collected in the same publication as the directlymeasured oxygen surface exchange coefficient. As indicated in the accompanying spreadsheet, when this was not possible, data from other literature studies was used.

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